

Dr Fernando Castro is the Head of Science for NPL's Electromagnetic & Electrochemical Technologies Department and the NPL's technical lead for Semiconductor metrology. He is an internationally renowned expert in metrology for advanced materials and semiconductors, with a strong track record of supporting technical innovation in industry leading to demonstrable impact. He has delivered over 80 invited/keynote/plenary talks in 20 countries. His scientific work has led to over 130 publications, including 70+ peer review papers, 3 book chapters and 3 patent families related to thin film electronics, nanotechnology and metrology. Dr. Castro was elected Fellow of the Institute of Physics, and Fellow of the Institute of Materials, Minerals and Mining (FIMMM), and was appointed Visiting Professor at the Advanced Technology Institute, University of Surrey. He also holds several distinguished international roles, including: Past Chair and Steering Committee member of VAMAS (a global intergovernmental pre-standards organisation), Vice-chair of the European Metrology Network on Advanced Manufacturing, Presidential Board member of the World Materials Institutes Research Forum, UK expert in international standards committee (IEC TC119 – Printed Electronics), among others. Dr Castro has significant experience in bidding, leading and delivering R&D projects, from small consultancy work to multimillion collaborative projects, including coordinating 3 large EU metrology projects and several national projects. He has provided invited expert advice to over 25 different peer-review scientific journals as well as to research funding agencies and science government departments in 4 countries.